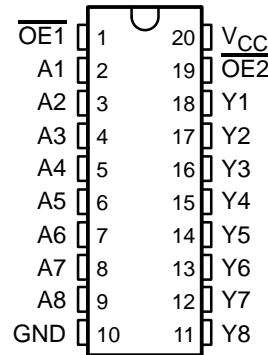


SN54LVTH541, SN74LVTH541 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

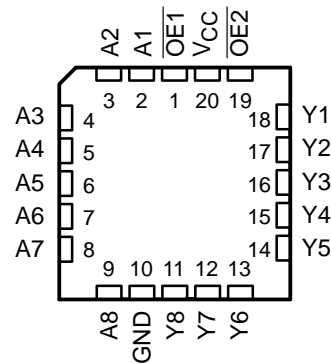
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- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low-Static Power Dissipation
- High-Impedance State During Power Up and Power Down
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V_{CC})
- Support Unregulated Battery Operation Down to 2.7 V
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$
- Power Off Disables Inputs/Outputs, Permitting Live Insertion
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Thin Very Small-Outline (DGV) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Ceramic (J) DIPs

SN54LVTH541 . . . J OR W PACKAGE
SN74LVTH541 . . . DB, DGV, DW, OR PW PACKAGE
(TOP VIEW)



SN54LVTH541 . . . FK PACKAGE
(TOP VIEW)



description

These octal buffers/drivers are designed specifically for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment.

The 'LVTH541 are ideal for driving bus lines or buffer memory address registers. These devices feature inputs and outputs on opposite sides of the package that facilitate printed circuit board layout.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable ($\overline{OE1}$ or $\overline{OE2}$) input is high, all outputs are in the high-impedance state.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

When V_{CC} is between 0 and 1.5 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54LVTH541 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74LVTH541 is characterized for operation from -40°C to 85°C .



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 **TEXAS
INSTRUMENTS**

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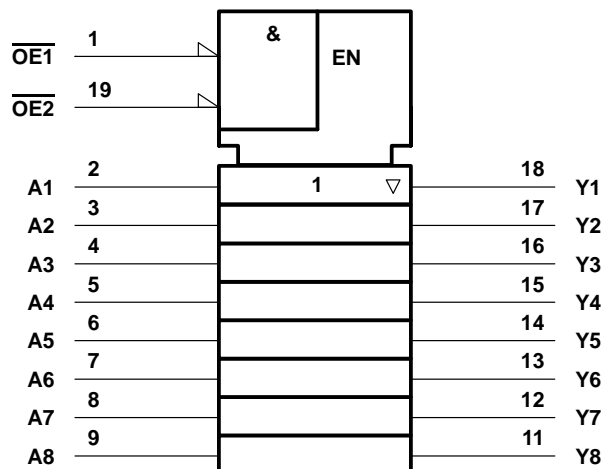
SN54LVTH541, SN74LVTH541 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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FUNCTION TABLE

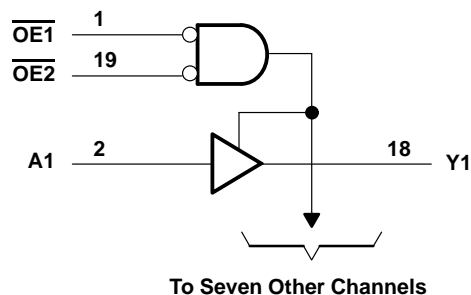
INPUTS			OUTPUT Y
OE1	OE2	A	
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



SN54LVTH541, SN74LVTH541 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high-impedance or power-off state, V_O (see Note 1)	–0.5 V to 7 V
Current into any output in the low state, I_O : SN54LVTH541	96 mA
SN74LVTH541	128 mA
Current into any output in the high state, I_O (see Note 2): SN54LVTH541	48 mA
SN74LVTH541	64 mA
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Package thermal impedance, θ_{JA} (see Note 3): DB package	115°C/W
DGV package	146°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

	SN54LVTH541		SN74LVTH541		UNIT
	MIN	MAX	MIN	MAX	
V_{CC} Supply voltage	2.7	3.6	2.7	3.6	V
V_{IH} High-level input voltage	2		2		V
V_{IL} Low-level input voltage		0.8		0.8	V
V_I Input voltage		5.5		5.5	V
I_{OH} High-level output current		–24		–32	mA
I_{OL} Low-level output current		48		64	mA
$\Delta t/\Delta v$ Input transition rise or fall rate		10		10	ns/V
$\Delta t/\Delta V_{CC}$ Power-up ramp rate		200		200	μ s/V
T_A Operating free-air temperature	–55	125	–40	85	°C

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

SN54LVTH541, SN74LVTH541 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54LVTH541			SN74LVTH541			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V _{IK}	V _{CC} = 2.7 V, I _I = -18 mA		-1.2			-1.2			V
V _{OH}	V _{CC} = 2.7 V to 3.6 V, I _{OH} = -100 μA		V _{CC} -0.2			V _{CC} -0.2			V
	V _{CC} = 2.7 V, I _{OH} = -8 mA		2.4			2.4			
	V _{CC} = 3 V	I _{OH} = -24 mA	2			2			
V _{OL}	V _{CC} = 2.7 V		I _{OL} = 100 μA		0.2		0.2		V
			I _{OL} = 24 mA		0.5		0.5		
	V _{CC} = 3 V		I _{OL} = 16 mA		0.4		0.4		
			I _{OL} = 32 mA		0.5		0.5		
			I _{OL} = 48 mA		0.55		0.55		
I _I	V _{CC} = 0 or 3.6 V, V _I = 5.5 V		10			10			μA
	Control inputs	V _{CC} = 3.6 V, V _I = V _{CC} or GND	±1			±1			
	Data inputs‡	V _{CC} = 3.6 V	V _I = V _{CC}		1		1		
			V _I = 0		-5		-5		
I _{off}	V _{CC} = 0, V _I or V _O = 0 to 4.5 V					±100			μA
I _I (hold)	Data inputs	V _{CC} = 3 V	V _I = 0.8 V		75		75		μA
			V _I = 2 V		-75		-75		
I _{OZH}	V _{CC} = 3.6 V, V _O = 3 V		5			5			μA
I _{OZL}	V _{CC} = 3.6 V, V _O = 0.5 V		-5			-5			μA
I _{OZPU} §	V _{CC} = 0 to 1.5 V, V _O = 0.5 V to 3 V, OE = Don't care		±100			±100			μA
I _{OZPD} §	V _{CC} = 1.5 V to 0, V _O = 0.5 V to 3 V, OE = Don't care		±100			±100			μA
I _{CC}	V _{CC} = 3.6 V, I _O = 0, V _I = V _{CC} or GND		Outputs high		0.19		0.19		mA
			Outputs low		5		5		
			Outputs disabled		0.19		0.19		
ΔI _{CC} ¶	V _{CC} = 3 V to 3.6 V, One input at V _{CC} - 0.6 V, Other inputs at V _{CC} or GND		0.2			0.2			mA
C _i	V _I = 3 V or 0		3			3			pF
C _o	V _O = 3 V or 0		7			7			pF

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

‡ Unused pins at V_{CC} or GND

§ This parameter is warranted but not production tested.

¶ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

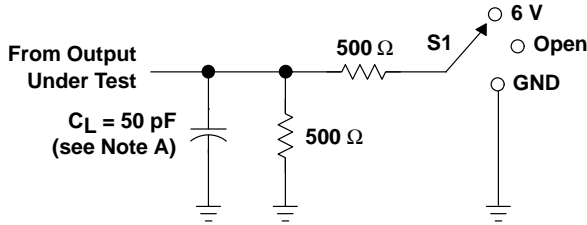
PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LVTH541				SN74LVTH541				UNIT	
			$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		$V_{CC} = 2.7\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$			$V_{CC} = 2.7\text{ V}$		
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN		MAX
t_{PLH}	A	Y	1	3.7		4	1.1	2.4	3.5		3.9	ns
t_{PHL}			1	3.7		4	1.1	2.4	3.5		3.9	
t_{PZH}	\overline{OE}	Y	1.4	5.3		6.3	1.5	3.5	5.2		6.2	ns
t_{PZL}			1.4	5.4		6	1.5	3.7	5.3		5.9	
t_{PHZ}	\overline{OE}	Y	1.4	5.8		6.1	1.5	3.9	5.6		5.9	ns
t_{PLZ}			1.4	5.4		5.7	1.5	3	5		5.3	

† All typical values are at $V_{CC} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$.

SN54LVTH541, SN74LVTH541
OCTAL BUFFERS/DRIVERS
WITH 3-STATE OUTPUTS

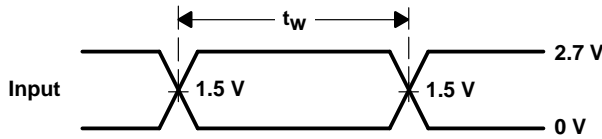
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PARAMETER MEASUREMENT INFORMATION

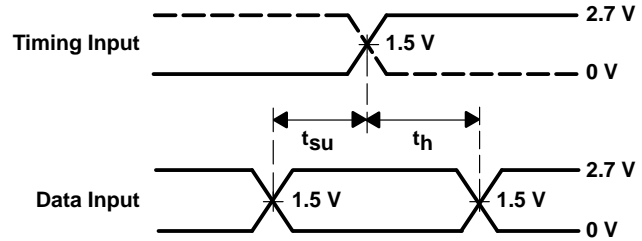


LOAD CIRCUIT

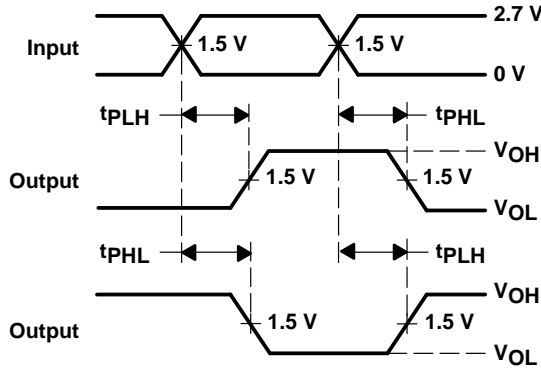
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



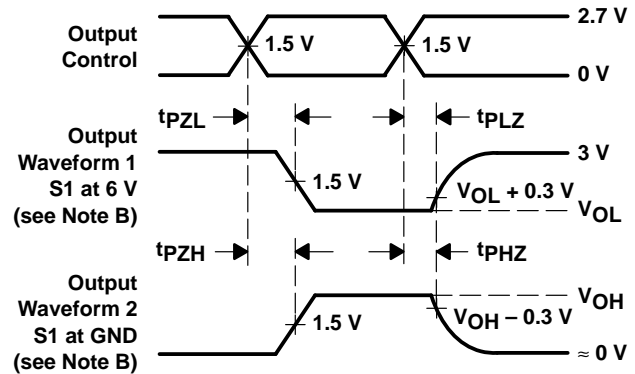
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PZL} and t_{PZH} are the same as t_{en} .
 - F. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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